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By: SPW:KMM:yce

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• Serial No. 10/813,257

• In the matter of the Application of: Kiyoshi TAKEKOSHI, et al.

• For: RELIABILITY EVALUATION TEST APPARATUS, RELIABILITY
EVALUATION TEST SYSTEM, CONTACTOR, AND RELIABILITY
EVALUATION TEST METHOD

Due Date: N/A

The following has been received in the U.S. Patent Office on the date stamped hereon:

- ☒ Dep. Acct. Order Form
- ☒ Cover Letter (*in duplicate*)
- ☒ Amendment under 37 C.F.R. § 1.312



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